

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-01

CB Certificate No.: 20001846 ITL

Schedule Number: IECQ-L ULTW 16.0003-01-S Rev No.: 5 Revision Date: 2022/07/15 Page 1 of 1

Appendix-1 (20001846 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3

